









**SN75HVD08, SN65HVD08** 

JAJSPZ7E - NOVEMBER 2002 - REVISED MARCH 2023

# SNx5HVD08 幅広い電源電圧範囲を持つ RS-485 トランシーバ

## 1 特長

- 3V~5.5V 電源で動作
- 無信号時電流電源の消費電力は 90mW 未満
- 開路、短絡、アイドル・バスのフェイルセーフ・レシーバ
- 1/8 ユニット負荷 (バス上に最大 256 ノード)
- 16kV HBM を超えるバス・ピンの ESD 保護
- 10Mbps で最適な信号品質を実現するためドライバ出 力電圧のスルーレートを制限
- ANSI TIA/EIA-485 標準と電気的に互換

## 2 アプリケーション

- ホストから電力を供給されるリモート・ステーションを使 用したデータ転送
- 絶縁型マルチポイント・データ・バス
- 産業用プロセス制御ネットワーク
- 販売時点情報管理ネットワーク
- 電気料金のメーター

## 3 説明

SN65HVD08 は、平衡データ転送用に設計された 3 ステ ート差動ライン・ドライバと差動ライン・レシーバを組み合わ せており、ANSI TIA/EIA-485-A および ISO-8482E 標準 に準拠したデバイスとの相互運用が可能です。

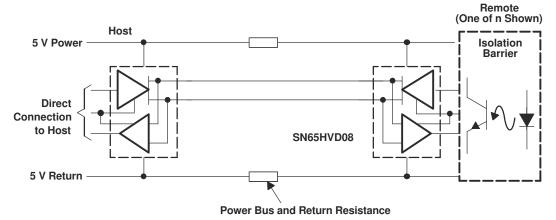
SN65HVD08 は、幅広い電源電圧範囲と低静止時電流 要件により、ケーブルの 5V 電源バスから最大 2V のライ ン電圧降下で動作します。ケーブルで電力を供給すること により、グランド絶縁バスの各接続で絶縁型電源を生成す る必要が軽減されます。

ドライバ差動出力とレシーバ差動入力は内部で接続され ており、差動入出力 (I/O) バス・ポートを形成しています。 この設計により、ドライバが無効になったり、電力が供給さ れなくなっても、バスへの負荷が最小限になります。ドライ バとレシーバはそれぞれアクティブ High、アクティブ Low のイネーブルを備えており、それらのイネーブルを外部で 互いに接続することで、方向制御として機能させることが できます。

### パッケージ情報

部品番号	パッケージ <sup>(1)</sup>	本体サイズ (公称)
SN75HVD08、	SOIC (8)	4.90mm x 3.91mm
SN65HVD08	PDIP (8)	9.81mm x 6.35mm

利用可能なパッケージについては、このデータシートの末尾にあ る注文情報を参照してください。



代表的なアプリケーション回路図



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## Changes from Revision C (July 2006) to Revision D (March 2015)

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## **5 Pin Configuration and Functions**

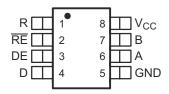


図 5-1. D or P Package, 8-Pin SOIC or PDIP (Top View)

表 5-1. Pin Functions

P	PIN TYPE		DESCRIPTION
NAME	NO.	IIPE	DESCRIPTION
А	6	Bus input / output	Driver output and receiver input (complementary to B)
В	7	Bus input / output	Driver output and receiver input (complementary to A)
D	4	Digital input	Driver data input
DE	3	Digital input	Driver enable high
GND	5	Reference potential	Local device ground
R	1	Digital output	Receive data output
RE	2	Digital input	Receiver enable low
V <sub>CC</sub>	8	Supply	3-V to 5.5-V supply

# 6 Specifications

## 6.1 Absolute Maximum Ratings

over operating free-air temperature range unless otherwise noted(1) (2)

	MIN	MAX	UNIT
Supply voltage, V <sub>CC</sub>	-0.3	6	V
Voltage at A or B	-9	14	V
Input voltage at D, DE, R or RE	-0.5	V <sub>CC</sub> + 0.5	V
Voltage input, transient pulse, A and B, through 100 $\Omega$	-25	25	V
Receiver output current, I <sub>O</sub>	-11	11	mA
Maximum Junction Temperature, T <sub>J</sub>		150	°C
Storage Temperature, T <sub>STG</sub>	-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### 6.2 ESD Ratings

					VALUE	UNIT
			Human body model (HBM), per ANSI/ESDA/JEDEC	A, B, and GND	16000	
1	$V_{(ESD)}$	Electrostatic discharge	JS-001 <sup>(1)</sup>	All pins	4000	V
			Charged-device model (CDM), per JEDEC specification JESD22-C101 <sup>(2)</sup>		1000	

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

<sup>(2)</sup> All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



# **6.3 Recommended Operating Conditions**

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		3		5.5	V
Input voltage at any bus terminal (se	eparately or common mode), V <sub>I</sub> <sup>(1)</sup>	<b>–7</b>		12	V
High-level input voltage, V <sub>IH</sub>	Driver, driver enable, and receiver enable inputs	2.25		V <sub>CC</sub>	V
Low-level input voltage, V <sub>IL</sub>	oriver, univer enable, and receiver enable inputs			8.0	V
Differential input voltage, V <sub>ID</sub>		-12		12	
I Bada I a a da a da a da a da a da a da	Driver	-60			mΛ
High-level output current, I <sub>OH</sub>	Receiver	-8			mA
Low level output ourrent	Driver			60	mA
Low-level output current, I <sub>OL</sub>	Receiver			8	ША
Operating free air temperature T	SN75HVD08	0		70	°C
Operating free-air temperature, T <sub>A</sub>	SN65HVD08	-40		85	C

<sup>(1)</sup> The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

## **6.4 Thermal Information**

	THERMAL METRIC(1)	D (SOIC) SN75 Version	D (SOIC) SN65 Version	P (PDIP)	UNIT
		8 PINS	8 PINS	8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	175.4	116.7	125	°C/W
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	53.6	56.3	34.9	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	45.1	63.4	23.7	°C/W
ΨЈТ	Junction-to-top characterization parameter	10.1	8.8	12.1	°C/W
ΨЈВ	Junction-to-board characterization parameter	44.4	62.6	23.6	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

### 6.5 Electrical Characteristics

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>OD</sub>	Driver differential output voltage magnitude	R <sub>L</sub> = 60 $\Omega$ , 375 $\Omega$ on each output to -7 V to 12 V, See $\boxed{2}$ 7-1	1.5		V <sub>CC</sub>	V
Δ V <sub>OD</sub>	Change in magnitude of driver differential output voltage	R <sub>L</sub> = 54 Ω	-0.2		0.2	V
V <sub>OC(PP)</sub>	Peak-to-peak driver common-mode output voltage	Center of two 27-Ω load resistors, See ⊠ 7-2		0.5		V
V <sub>IT+</sub>	Positive-going receiver differential input voltage threshold				-10	mV
V <sub>IT-</sub>	Negative-going receiver differential input voltage threshold		-200			mV
V <sub>hys</sub>	Receiver differential input voltage threshold hysteresis(V <sub>IT+</sub> - V <sub>IT-</sub> )			35		mV
V <sub>OH</sub>	Receiver high-level output voltage	I <sub>OH</sub> = -8 mA	2.4			V
V <sub>OL</sub>	Receiver low-level output voltage	I <sub>OL</sub> = 8 mA			0.4	V
I <sub>IH</sub>	Driver input, driver enable, and receiver enable high-level input current		-100		100	μΑ
I <sub>IL</sub>	Driver input, driver enable, and receiver enable low-level input current		-100		100	μΑ
Ios	Driver short-circuit output current	7 V < V <sub>O</sub> < 12 V	-265		265	mA

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## **6.5 Electrical Characteristics (continued)**

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		V <sub>I</sub> = 12 V			130	
	Rue input current (disabled driver)	V <sub>I</sub> = -7 V	-100			
"		V <sub>I</sub> = 12 V, V <sub>CC</sub> = 0 V			130	μA
		V <sub>I</sub> = -7 V. V <sub>CC</sub> = 0 V	-100			
		Receiver enabled, driver disabled, no load			10	mA
I <sub>CC</sub>	Supply current	Driver enabled, receiver disabled, no load			16	IIIA
		Both disabled			5	μΑ
		Both enabled, no load			16	mA

## **6.6 Driver Switching Characteristics**

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PHL</sub>	Driver high-to-low propagation delay time		18		40	
t <sub>PLH</sub>	Driver low-to-high propagation delay time		18		40	
t <sub>r</sub>	Driver 10%-to-90% differential output rise time	$R_L$ = 54 Ω, $C_L$ = 50 pF,See $\boxtimes$ 7-3	10	•	55	ns
t <sub>f</sub>	Driver 90%-to-10% differential output fall time		10		55	
t <sub>SK(P)</sub>	Driver differential output pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>				2.5	
	Driver enable time	Receiver enabled, See Figures 4 and 5			55	ns
t <sub>en</sub>	Driver enable time	Receiver disabled, See Figures 4 and 5			6	μs
t <sub>dis</sub>	Driver disable time	Receiver enabled, See Figures 4 and 5			90	ns

## **6.7 Receiver Switching Characteristics**

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PHL</sub>	Receiver high-to-low propagation delay time				70	
t <sub>PLH</sub>	Receiver low-to-high propagation delay time				70	
t <sub>r</sub>	Receiver 10%-to-90% differential output rise time	C <sub>L</sub> = 15 pF, See ⊠ 7-6	5			ns
t <sub>f</sub>	Receiver 90%-to-10% differential output fall time				5	
t <sub>SK(P)</sub>	Receiver differential output pulse skew,  t <sub>PHL</sub> - t <sub>PLH</sub>				4.5	
	Receiver enable time	Driver enabled, See ⊠ 7-7			15	ns
l <sup>t</sup> en	Receiver enable time	Driver disabled, See ☑ 7-8			6	μs
t <sub>dis</sub>	Receiver disable time	Driver enabled, See ☑ 7-7			20	ns



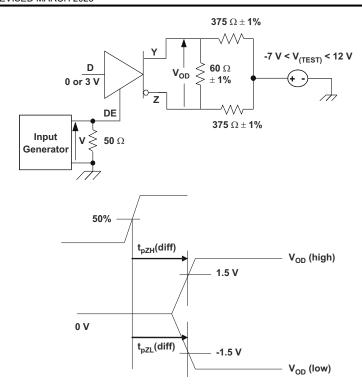
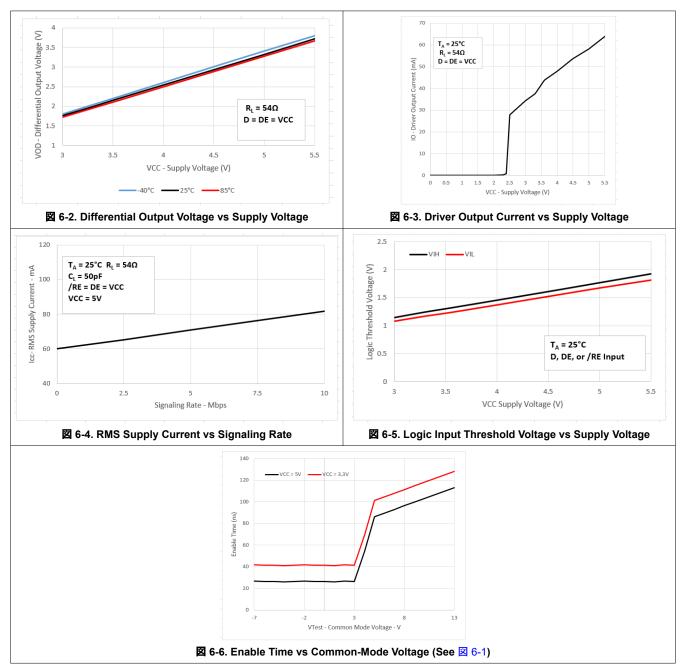


図 6-1. Driver Enable Time From DE to  $V_{\text{OD}}$ 

The time  $t_{pZL}(x)$  is the measure from DE to  $V_{OD}(x)$ .  $V_{OD}$  is valid when it is greater than 1.5 V.

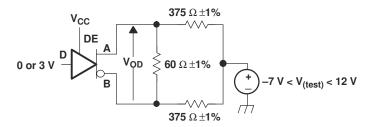


## **6.8 Typical Characteristics**

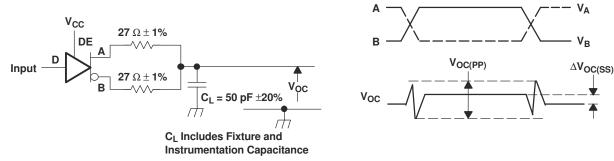




## 7 Parameter Measurement Information

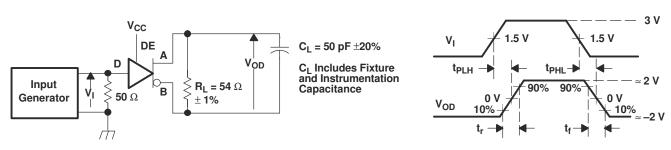


☑ 7-1. Driver V<sub>OD</sub> With Common-Mode Loading Test Circuit



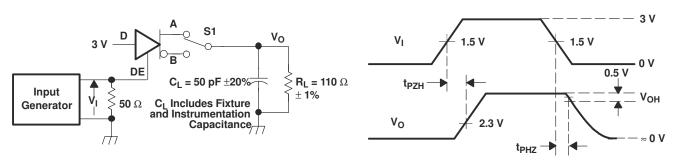
Input: PRR = 500 kHz, 50% Duty Cycle, $t_r$ <6ns,  $t_f$ <6ns,  $Z_O$  = 50  $\Omega$ 

## 図 7-2. Test Circuit and Definitions for the Driver Common-Mode Output Voltage



Generator: PRR = 500 kHz, 50% Duty Cycle,  $t_r$  <6 ns,  $t_f$  <6 ns,  $Z_o$  = 50  $\Omega$ 

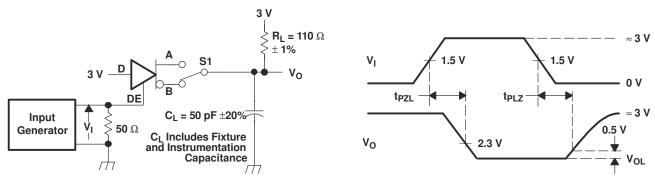
### 図 7-3. Driver Switching Test Circuit and Voltage Waveforms



Generator: PRR = 500 kHz, 50% Duty Cycle,  $t_r$  <6 ns,  $t_f$  <6 ns,  $Z_o$  = 50  $\Omega$ 

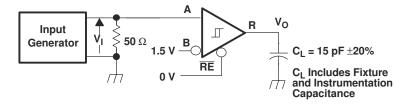
### 図 7-4. Driver High-Level Enable and Disable Time Test Circuit and Voltage Waveforms



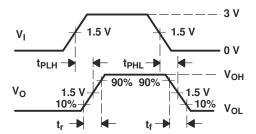


Generator: PRR = 500 kHz, 50% Duty Cycle,  $t_r$  <6 ns,  $t_f$  <6 ns,  $Z_o$  = 50  $\Omega$ 

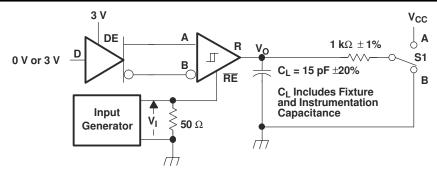
## 図 7-5. Driver Low-Level Output Enable and Disable Time Test Circuit and Voltage Waveforms



Generator: PRR = 500 kHz, 50% Duty Cycle,  $t_r$  <6 ns,  $t_f$  <6 ns,  $Z_o$  = 50  $\Omega$ 



☑ 7-6. Receiver Switching Test Circuit and Voltage Waveforms



Generator: PRR = 500 kHz, 50% Duty Cycle,  $t_r$  <6 ns,  $t_f$  <6 ns,  $Z_o$  = 50  $\Omega$ 

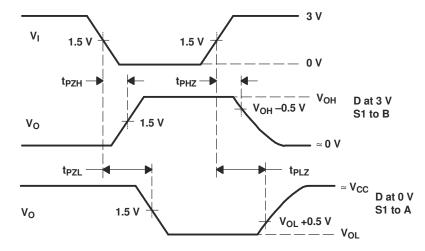
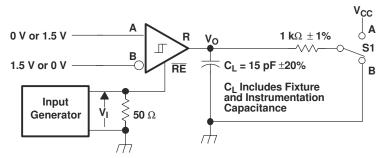


図 7-7. Receiver Enable and Disable Time Test Circuit and Voltage Waveforms With Drivers Enabled





Generator: PRR = 100 kHz, 50% Duty Cycle,  $t_r$  <6 ns,  $t_f$  <6 ns,  $Z_o$  = 50  $\Omega$ 

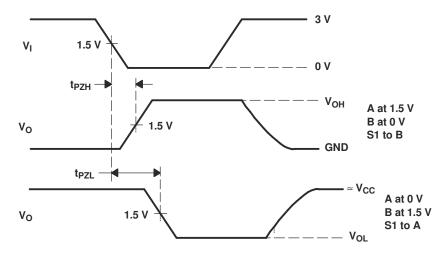


図 7-8. Receiver Enable Time From Standby (Driver Disabled)



## **8 Detailed Description**

## 8.1 Overview

The SNx5HVD08 is a 3-V to 5.5-V, half-duplex, RS-485 transceiver suitable for data transmission up to 10 Mbps.

This device has an active-high driver enable and active-low receiver enable. A standby current of less than 5  $\mu$ A can be achieved by disabling both driver and receiver.

Device operation is specified over a wide temperature range from -40°C to +85°C.

## 8.2 Functional Block Diagram

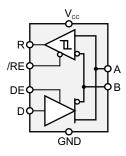


図 8-1. Logic Diagram (Positive)

## 8.3 Feature Description

Internal ESD protection circuits protect the transceiver bus terminals against ±16 kV Human Body Model (HBM) electrostatic discharges and all other pins up to ±4 kV.

The SNx5HVD08 provides internal biasing of the receiver input thresholds for open-circuit, bus-idle, or short-circuit failsafe conditions, and a typical receiver hysteresis of 35 mV.

### 8.4 Device Functional Modes

表 8-1. Function Table: Driver

INPUT	ENABLE	OUT	PUTS
D	DE	Α	В
Н	Н	Н	L
L	Н	L	Н
X	L	Z	Z
Open	Н	Н	L

表 8-2. Function Table: Receiver

DIFFERENTIAL INPUTS	ENABLE <sup>(1)</sup>	OUTPUT <sup>(1)</sup>
$V_{ID} = V_A - V_B$	RE	R
V <sub>ID</sub> ≤ -0.2 V	L	L
-0.2 V < V <sub>ID</sub> < -0.01 V	L	?
-0.01 V ≤ V <sub>ID</sub>	L	Н
X	H	Z
Open Circuit	L	Н
Short Circuit	L	Н

H = high level; L = low level; Z = high impedance; X = irrelevant;
? = indeterminate



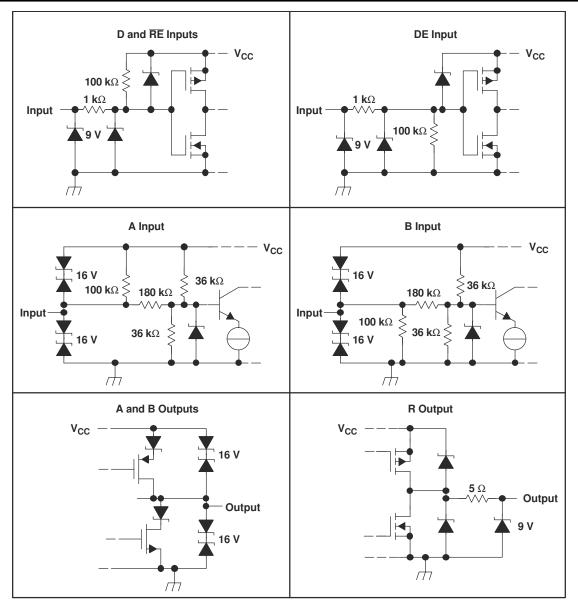


図 8-2. Equivalent Input and Output Schematic Diagrams

## 9 Application and Implementation

注

以下のアプリケーション情報は、TIの製品仕様に含まれるものではなく、TIではその正確性または完全性を保証いたしません。個々の目的に対する製品の適合性については、お客様の責任で判断していただくことになります。お客様は自身の設計実装を検証しテストすることで、システムの機能を確認する必要があります。

### 9.1 Application Information

As electrical loads are physically distanced from their power source, the effects of supply and return line impedance and the resultant voltage drop must be accounted. If the supply regulation at the load cannot be maintained to the circuit requirements, it forces the use of remote sensing, additional regulation at the load, bigger or shorter cables, or a combination of these. The SN65HVD08 eases this problem by relaxing the supply requirements to allow for more variation in the supply voltage over typical RS-485 transceivers.

### 9.1.1 Supply Source Impedance

In the steady state, the voltage drop from the source to the load is simply the wire resistance times the load current as modeled in  $\boxtimes$  9-1.

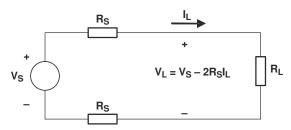


図 9-1. Steady-State Circuit Model

For example, if you were to provide 5-V ±5% supply power to a remote circuit with a maximum load requirement of 0.1 A (one SN65HVD08), the voltage at the load would fall below the 4.5-V minimum of most 5-V circuits with as little as 5.8 m of 28-GA conductors. 表 9-1 summarizes wire resistance and the length for 4.5 V and 3 V at the load with 0.1 A of load current. The maximum lengths would scale linearly for higher or lower load currents.

WIRE SIZE	RESISTANCE	4.5-V LENGTH AT 0.1 A	3-V LENGTH AT 0.1 A
28 Gauge	0.213 Ω/m	5.8 m	41.1 m
24 Gauge	0.079 Ω/m	15.8 m	110.7 m
22 Gauge	0.054 Ω/m	23.1 m	162.0 m
20 Gauge	0.034 Ω/m	36.8 m	257.3 m
18 Gauge	0.021 Ω/m	59.5 m	416.7 m

表 9-1. Maximum Cable Lengths for Minimum Load Voltages at 0.1 A Load

Under dynamic load requirements, the distributed inductance and capacitance of the power lines may not be ignored and decoupling capacitance at the load is required. The amount depends upon the magnitude and frequency of the load current change but, if only powering the SN65HVD08, a 0.1  $\mu$ F ceramic capacitor is usually sufficient.

### 9.1.2 Opto-Isolated Data Buses

Long RS-485 circuits can create large ground loops and pick up common-mode noise voltages in excess of the range tolerated by standard RS-485 circuits. A common remedy is to provide galvanic isolation of the data circuit from earth or local grounds.

Transformers, capacitors, or phototransistors most often provide isolation of the bus and the local node. Transformers and capacitors require changing signals to transfer the information over the isolation barrier and phototransistors (opto-isolators) can pass steady-state signals. Each of these methods incurs additional costs and complexity, the former in clock encoding and decoding of the data stream and the latter in requiring an isolated power supply.

Quite often, the cost of isolated power is repeated at each node connected to the bus as shown in  $\boxtimes$  9-2. The possibly lower-cost solution is to generate this supply once within the system and then distribute it along with the data line(s) as shown in  $\boxtimes$  9-3.

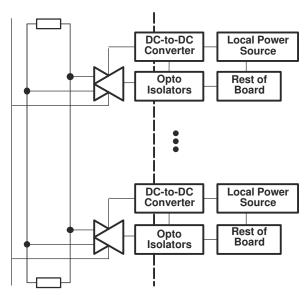


図 9-2. Isolated Power at Each Node

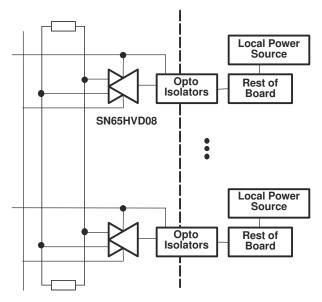


図 9-3. Distribution of Isolated Power

The features of the SN65HVD08 are particularly good for the application of  $\boxtimes$  9-3. Due to added supply source impedance, the low quiescent current requirements and wide supply voltage tolerance allow for the poorer load regulation.



### 9.1.3 Opto Alternative

The ISO150 is a two-channel, galvanically isolated data coupler capable of data rates of 80 Mbps. Each channel can be individually programmed to transmit data in either direction.

Data is transmitted across the isolation barrier by coupling complementary pulses through high-voltage 0.4-pF capacitors. Receiver circuitry restores the pulses to standard logic levels. Differential signal transmission rejects isolation-mode voltage transients up to 1.6 kV/ms.

ISO150 avoids the problems commonly associated with opto-couplers. Optically-isolated couplers require high current pulses and allowance must be made for LED aging. The ISO150's Bi-CMOS circuitry operates at 25 mW per channel with supply voltage range matching that of the SN65HVD08 of 3 V to 5.5 V.

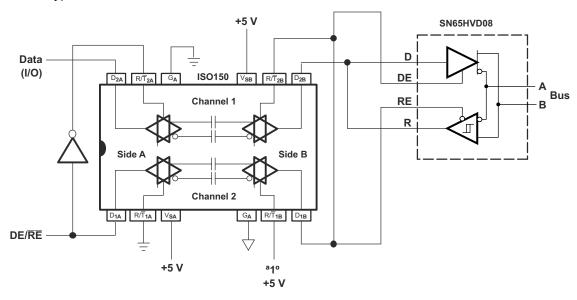


図 9-4. Isolated RS-485 Interface

## 9.2 Typical Application

An RS-485 bus consists of multiple transceivers connecting in parallel to a bus cable. To eliminate line reflections, each cable end is terminated with a termination resistor,  $R_T$ , whose value matches the characteristic impedance,  $Z_0$ , of the cable. This method, known as parallel termination, allows for higher data rates over longer cable length.

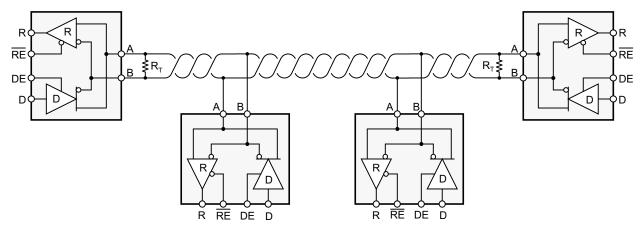


図 9-5. Typical Application Diagram

### 9.2.1 Design Requirements

RS-485 is a robust electrical standard suitable for long-distance networking that may be used in a wide range of applications with varying requirements, such as distance, data rate, and number of nodes.

### 9.2.1.1 Data Rate and Bus Length

There is an inverse relationship between data rate and bus length, meaning the higher the data rate, the shorter the cable length; and conversely, the lower the data rate, the longer the cable may be without introducing data errors. While most RS-485 systems use data rates between 10 kbps and 100 kbps, some applications require data rates up to 250 kbps at distances of 4000 feet and longer. Longer distances are possible by allowing for small signal jitter of up to 5 or 10%.

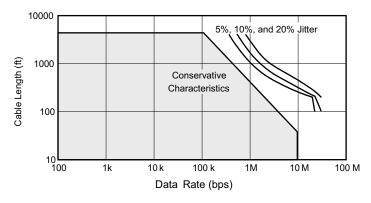


図 9-6. Cable Length vs Data Rate Characteristic



### 9.2.1.2 Stub Length

When connecting a node to the bus, the distance between the transceiver inputs and the cable trunk, known as the stub, should be as short as possible. Stubs present a non-terminated piece of bus line which can introduce reflections as the length of the stub increases. As a general guideline, the electrical length, or round-trip delay, of a stub should be less than one-tenth of the rise time of the driver, thus giving a maximum physical stub length as shown in  $\pm 1$ .

$$L_{\text{stub}} \le 0.1 \times t_{\text{r}} \times v \times c \tag{1}$$

#### Where:

- t<sub>r</sub> is the 10/90 rise time of the driver
- c is the speed of light (3 × 10<sup>8</sup> m/s)
- v is the signal velocity of the cable or trace as a factor of c

Per 式 1, the maximum recommended stub length for the minimum driver output rise time of the SNx5HVD08 for a signal velocity of 78% is 0.23 meters (0.75 feet).

### 9.2.1.3 Bus Loading

The RS-485 standard specifies that a compliant driver must be able to driver 32 unit loads (UL), where 1 unit load represents a load impedance of approximately 12 k $\Omega$ . Because the SN65HVD08 and SN75HVD08 are each 1/8 UL transceivers, it is possible to connect up to 256 receivers to the bus.

#### 9.2.1.4 Receiver Failsafe

The differential receivers of the SNx5HVD08 family are "failsafe" to invalid bus states caused by:

- · Open bus conditions, such as a disconnected connector
- Shorted bus conditions, such as cable damage shorting the twisted-pair together
- Idle bus conditions that occur when no driver on the bus is actively driving

In any of these cases, the differential receiver will output a failsafe logic High state so that the output of the receiver is not indeterminate.

Receiver failsafe is accomplished by offsetting the receiver thresholds such that the "input indeterminate" range does not include zero volts differential.

In order to comply with the RS-422 and RS-485 standards, the receiver output must output a High when the differential input VID is more positive than +200 mV, and must output a Low when VID is more negative than -200 mV. The receiver parameters which determine the failsafe performance are VIT(+) and VIT(-).

As shown in the Electrical Characteristics table, differential signals more negative than -200 mV will always cause a Low receiver output, and differential signals more positive than -10 mV will always cause a High receiver output. Thus, when the differential input signal is close to zero, it is still above the maximum VIT(+) threshold of -10 mV, and the receiver output will be High.



### 9.2.2 Detailed Design Procedure

In order to protect bus nodes against high-energy transients, the implementation of external transient protection devices is necessary.

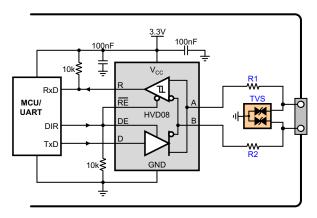


図 9-7. Transient protection against ESD, EFT, and Surge transients

表 9-2. Bill of Materials

DEVICE	FUNCTION	ORDER NUMBER	MANUFACTURER
XCVR	3.3 V to 5 V, 10 Mbps RS-485 Transceiver	SNx5HVD08	TI
R1, R2	10 Ω, Pulse-Proof Thick-Film Resistor	CRCW0603010RJNEAHP	Vishay
TVS	Bidirectional 400 W Transient Suppressor	CDSOT23-SM712	Bourns

### 9.2.3 Application Curve

☑ 9-8 demonstrates operation of the SN65HVD08 at a signaling rate of 10 Mbps.

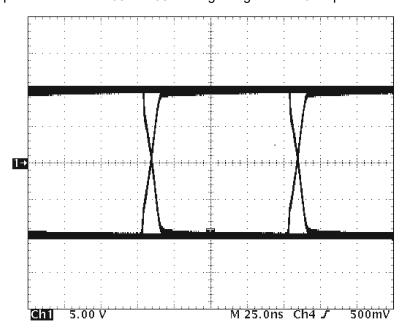


図 9-8. SNx5HVD08 Differential Output Waveform

## 9.3 Power Supply Recommendations

To ensure reliable operation at all data rates and supply voltages, each supply should be buffered with a 100-nF ceramic capacitor located as close to the supply pins as possible. The TPS76333 and TPS76350 are linear voltage regulators suitable for 3.3 V and 5 V supplies respectively.

### 9.4 Layout

### 9.4.1 Layout Guidelines

On-chip IEC-ESD protection is sufficient for laboratory and portable equipment but insufficient for EFT and surge transients occurring in industrial environments. Therefore, robust and reliable bus node design requires the use of external transient protection devices.

Because ESD and EFT transients have a wide frequency bandwidth from approximately 3 MHz to 3 GHz, high frequency layout techniques must be applied during PCB design.

- 1. Place the protection circuitry close to the bus connector to prevent noise transients from entering the board.
- 2. Use VCC and ground planes to provide low-inductance. Note that high-frequency currents follow the path of least inductance and not the path of least impedance.
- 3. Design the protection components into the direction of the signal path. Do not force the transient currents to divert from the signal path to reach the protection device.
- 4. Apply 100-nF to 220-nF bypass capacitors as close as possible to the VCC-pins of transceiver, UART, or controller ICs on the board.
- 5. Use at least two vias for VCC and ground connections of bypass capacitors and protection devices to minimize effective via-inductance.
- 6. Use 1-k $\Omega$  to 10-k $\Omega$  pullup and pulldown resistors for enable lines to limit noise currents in these lines during transient events.
- 7. Insert series pulse-proof resistors into the A and B bus lines if the TVS clamping voltage is higher than the specified maximum voltage of the transceiver bus terminals. These resistors limit the residual clamping current into the transceiver and prevent it from latching up.
- 8. While pure TVS protection is sufficient for surge transients up to 1 kV, higher transients require metal-oxide varistors (MOVs) which reduce the transients to a few hundred volts of clamping voltage, and transient blocking units (TBUs) that limit transient current to less than 1 mA.

### 9.4.2 Layout Example

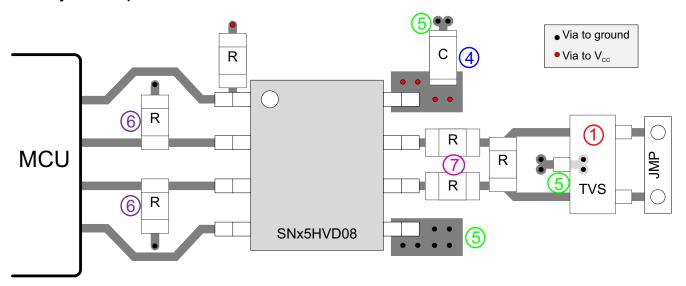


図 9-9. SNx5HVD08 Layout example

## 10 Device and Documentation Support

## 10.1 Device Support

## 10.1.1 サード・パーティ製品に関する免責事項

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ESD による破損は、わずかな性能低下からデバイスの完全な故障まで多岐にわたります。精密な IC の場合、パラメータがわずかに変化するだけで公表されている仕様から外れる可能性があるため、破損が発生しやすくなっています。

### 10.5 用語集

テキサス・インスツルメンツ用語集 この用語集には、用語や略語の一覧および定義が記載されています。

## 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material			Part marking
	(1)	(2)			(0)	(4)	(5)		(0)
SN65HVD08D	Obsolete	Production	SOIC (D)   8	-	-	Call TI	Call TI	-40 to 85	VP08
SN65HVD08DR	Active	Production	SOIC (D)   8	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP08
SN65HVD08DR.A	Active	Production	SOIC (D)   8	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP08
SN65HVD08DRG4	Active	Production	SOIC (D)   8	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP08
SN65HVD08P	Active	Production	PDIP (P)   8	50   TUBE	Yes	NIPDAU	N/A for Pkg Type	-40 to 85	65HVD08
SN65HVD08P.A	Active	Production	PDIP (P)   8	50   TUBE	Yes	NIPDAU	N/A for Pkg Type	-40 to 85	65HVD08
SN75HVD08D	Obsolete	Production	SOIC (D)   8	-	-	Call TI	Call TI	0 to 70	VN08
SN75HVD08DR	Obsolete	Production	SOIC (D)   8	-	-	Call TI	Call TI	0 to 70	VN08
SN75HVD08P	Active	Production	PDIP (P)   8	50   TUBE	Yes	NIPDAU	N/A for Pkg Type	0 to 70	75HVD08
SN75HVD08P.A	Active	Production	PDIP (P)   8	50   TUBE	Yes	NIPDAU	N/A for Pkg Type	0 to 70	75HVD08

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(2)</sup> Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.



## PACKAGE OPTION ADDENDUM

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and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

# **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

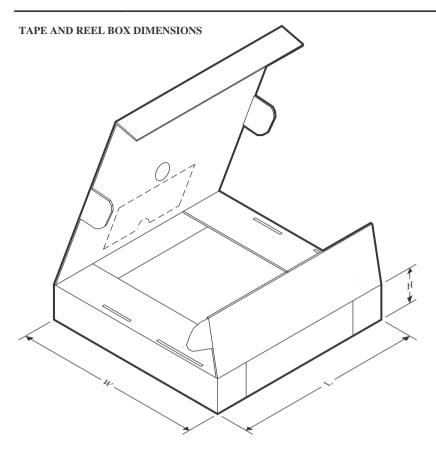


#### \*All dimensions are nominal

Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65HVD08DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

# **PACKAGE MATERIALS INFORMATION**

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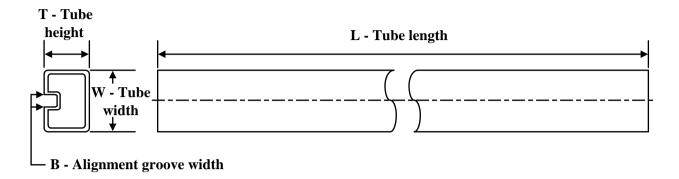
### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65HVD08DR	SOIC	D	8	2500	340.5	336.1	25.0

# **PACKAGE MATERIALS INFORMATION**

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## **TUBE**



\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN65HVD08P	Р	PDIP	8	50	506	13.97	11230	4.32
SN65HVD08P.A	Р	PDIP	8	50	506	13.97	11230	4.32
SN75HVD08P	Р	PDIP	8	50	506	13.97	11230	4.32
SN75HVD08P.A	Р	PDIP	8	50	506	13.97	11230	4.32



SMALL OUTLINE INTEGRATED CIRCUIT



### NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# P (R-PDIP-T8)

# PLASTIC DUAL-IN-LINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001 variation BA.



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